


<b>Search Notes</b> 	<b>Application/Control No.</b> 10565863	<b>Applicant(s)/Patent Under Reexamination</b> TAKAISHI, YOSHITOMO
	<b>Examiner</b> JOHN W LEE	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	132	6/3/2009	John W. Lee
382	168	6/10/2010	John W. Lee

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor Search	6/3/2009	John W. Lee
EAST Search	6/3/2009	John W. Lee
IEEE Search	6/3/2009	John W. Lee
EAST Search	11/20/2009	John W. Lee
Plus Search	6/9/2010	John W. Lee
Inventor Search (using EDAN)	6/9/2010	John W. Lee
Inventor Search (using EAST)	6/9/2010	John W. Lee
382/128 and 382/132 (combined with keyword)	6/9/2010	John W. Lee
EAST Search	6/9/2010	John W. Lee
Science direct.com Search	6/10/2010	John W. Lee
IEEE Search	6/10/2010	John W. Lee

INTERFERENCE SEARCH			
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